



Report Title:	Reliability Report RQR08620 ADIS16489BMLZ-P With Parylene coating.
Report Number:	08620
Revision:	Α

02/09/17

Date:



Summary

This report documents the successful completion of the reliability qualification requirements for the use of Parylene coating on the assembled PCB as a mitigation effort relative to tin whisker formation on ADIS16489 devices.

Product Description

Tactical grade 7 degrees of freedom MEMS inertial sensor.

Table 1: Product Characteristics

Package (outer configuration)	24-Lead Module with Connector		
	Interface.		
Body Size (mm)	47mm x 44mm x 14mm		
Assembly Site	Engent		
SMT Solder	Sn96.5/Ag3.0/0.5Cu		
Underfill	Hysol 4545FC		
Adhesive(s)	Loctite 3563		
Lead Finish	Au plate		
Coating material	Parylene C		

Package/Assembly



Description / Results of Tests Performed

Tables 2 and 3 provide a description of the qualification tests conducted and the associated test results for products manufactured on the same technologies as described in Table 1. All devices were electrically tested before and after each stress. Any device that did not meet all electrical data sheet limits following stressing would be considered a valid (stress-attributable) failure unless there was conclusive evidence to indicate otherwise.

Test Name	Specification	Conditions	Device	Lot #	Sample Size	Qty. Failures
Temperature Cycle	JESD22-A104	Condition N -40⁰C to +85 ⁰C 1000 cycles	ADIS16489-P	AD00001566	16	0
HTOL	MIL-STD-883 TM1015	+110 ℃ Ta 500 Hr.	ADIS16489-P	AD00001566	16	0
Mechanical Shock	MIL-STD-883 TM 2002	2000g.	ADIS16489-P	AD00001566	5	0

Table 2: Qualification Test Results



Table 3: Qualification Extension Data

Qual Test						
	Ref. Spec	Conditions	Duration	Device Type	Sample Size	# Rejects
HTOL	MIL-STD-883 TM1015	+85°C Ta	500 Hours	ADIS16488	15	0
Temperature Cycle	JESD22-A104	Condition N -40°C to +85°C	500 Cycles	ADIS16488	10	0
Handling Shock	MIL-STD-883 Mtd 2002.4	2000g	6 positions	ADIS16488	3	0
Random Vibration	MIL-STD-202 Mtd 214A	Condition C	8 hrs.	ADIS16488	6	0
ADIS16485 CLX-13	0818-000 with par	ylene coating.				
Temperature	JESD22-A104	Condition A	1000 Cycles	CI X 420040	15	
Cycle	313022 7(104	-55°C to +85°C		CLX-130818- 000	13	0
	MIL-STD-883 TM1015		500 Hours		15	0



Qual Test	Ref. Spec	Conditions	Duration	Device Type	Sample Size	# Rejects
HTOL	MIL-STD-883 TM1015	+110°C Ta	500 Hours	CLX-130818- 100	16	0
	TM1015			100		



ESD Test Results

Data for ESD Characterization is extended from the ADW22037, ADSP-BF512, ADM6711, ADCMP350, ADP2102, ADG849, AD7689, ADR361, ADP121, ADP3330, AD8629 and ADXRS646 monolithic qualification data.

Table 4: QUALIFICATION EXTENSION DATA ESD Characterization Results

DEVICE	TEST METHOD	HIGHEST PASS LEVEL	CLASS	
ADXL203E (ADW22037Z)	ESD Assoc. STM5.1-1998	3500V	2	
ADSP-BF512	F512 ESD Assoc. 4000V STM5.1-1998		3A	
ADM6711	ESD Assoc. STM5.1-1998	3000∨	2	
ADCMP350	ESD Assoc. STM5.1-1998	3500V	2	
ADP2102	ESD Assoc. STM5.1-1998	2500V	2	
ADG849	ESD Assoc. STM5.1-1998	2000V	2	
AD7689	ESD Assoc. STM5.1-1998			
ADR361	ESD Assoc. STM5.1-1998	3000∨	2	
ADP121	ESD Assoc. STM5.1-1998	2000V	2	
ADP3330	330 ESD Assoc. 2000V STM5.1-1998		2	
AD8629	ESD Assoc. STM5.1-1998	1500V	1C	
ADXRS646	ESD Assoc. STM5.1-1998	1500V	1C	



Approvals

Reliability Engineer: David Hensley

Additional Information

Data sheets and other additional information are available on <u>Analog Devices' web site</u>